Notice of References Cited Application/Control No. 10/617,628 Examiner Marcus Charles Applicant(s)/Patent Under Reexamination SERKH ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
·	Α	US-4,504,252	03-1985	Honma, Masayuki	474/112
	В	US-4,571,222	02-1986	Brandenstein et al.	474/112
	U	US-4,605,387	08-1986	Okubo et al.	474/112
	ם	US-5,820,503	10-1998	Bruchner et al.	474/112
	Ε	US-6,364,795	04-2002	Komorowski et al.	474/135
	F	US-			
	G	US-			
	Н	US-			
	I	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP(02-118249) A	05-1990	Japan	Hayashi	474/112
	0	JP(02-118251) A	05-1990	Japan	Hayashi	474/112
	Р	JP(03-288048) A	12-1991	Japan	Tanaka	474/112
÷	σ	JP(10-267094) A	10-1998	Japan		F16H 7/12
	R	JP(59-083857) A	05-1984	Japan	Shoda et al.	F16H 7/12
	s	JP(62-151657) A	07-1987	Japan		F16H 7/12
	Т	EP(0053954) B1	03-1984	European	Bortolussi	F16H 7/12

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.